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				Filing Date	Filed: January 4, 2002	
STATEMENT BY APPLICANT (use as many streets as mecessary)				First Named Inventor	Naoaki YAMAGUCH et al.	
			my)	Group Art Uait	1765	
				Examiner Name	Anita Karen Alanko	
Sheet	1	of	3	Attorney Docket Number	0756-7191	

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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.